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Form PTO-1449 (REV. 8-83)	US Dept. of Commerce		ATTY DOCKET NO. 115975		APPLICATION NO. 10/632,823					
INFO	RMATI	ION DISCLOSURE STATEMENT								
(Use several sheets if necessary)		APPLICANT(S) Vidya VENKATACHALAM								
				FILING DATE August 4, 2003		GROUP 2613				
		U.S. PA	TENT DOC	UMENTS						
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	·	OTHER DOCUMENTS (Include	ling Author,	Title, Date, Pertinent Page	es, etc.)					
NB	1	Lambert et al., "Thickness Measurement of Food Packing Films," 5th International Conference on Quality Control By Artificial Vision, pp. 287-291, May 1999.								
NB	2	Doudkin et al., "Contour Extraction Algorithms for LSI Circuit Video Image Processing," Proceedings of the International Workshop on Intelligent Data Acquisition and Advanced Computing Systems: Technology and Applications, pp. 69-72, July 2001.								
NB	3	Allada et al., "Efficient Vertex Detection Algorithms Using the Hough Transform," International Journal of Advanced Manufacturing Technology, Vol. 11, No. 6, pp. 394-405, 1996.								
EXAMINER /Nathan Bloom/					DATE CONSIDERED 02/15/2007					
Examiner: In	nitial if	citation considered, whether or not citation	on is in con	nformance with M.P.E.P.	609; draw line the	hrough citati	on if not in			
	ATTIOL (1)	ance and not considered. Include copy of th	is torm with	inexi communication to a	ррисант.					

Date: January 4, 2006